

<b>Notice of References Cited</b>	Application/Control No. 10/772,555		Applicant(s)/Patent Under Reexamination SMITH ET AL.	
	Examiner BEN C. WANG		Art Unit 2192	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0111708 A1	06-2004	Calder et al.	717/131
*	B	US-2004/0216097 A1	10-2004	Sun, Mingqiu	717/154
*	C	US-2004/0216082 A1	10-2004	Sun, Mingqiu	717/100
	D	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

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	N					
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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Sherwood et al., "Automatically Characterizing Large Scale Program Behavior", 2002 ACM, pp. 45-57
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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